
Nanotehnologije - Slovar - 6. del: Karakterizacija nanoobjektov (ISO/PRF TS 80004-6:2020)

Nanotechnologies - Vocabulary - Part 6: Nano-object characterization (ISO/PRF TS 80004-6:2020)

Nanotechnologien - Fachwörterverzeichnis - Teil 6: Charakterisierung von Nanoobjekten (ISO/PRF TS 80004-6:2020)

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SPECIFICATION

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80004-6

Second edition

**Nanotechnologies — Vocabulary —
Part 6:
Nano-object characterization**

Nanotechnologies — Vocabulaire —

Partie 6: Caractérisation des nano-objets

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Member bodies are requested to consult relevant national interests in IEC/TC 113 before casting their ballot to the e-Balloting application.

PROOF / ÉPREUVE



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Foreword

ISO (the International Organization for Standardization) is a worldwide federation of national standards bodies (ISO member bodies). The work of preparing International Standards is normally carried out through ISO technical committees. Each member body interested in a subject for which a technical committee has been established has the right to be represented on that committee. International organizations, governmental and non-governmental, in liaison with ISO, also take part in the work. ISO collaborates closely with the International Electrotechnical Commission (IEC) on all matters of electrotechnical standardization.

The procedures used to develop this document and those intended for its further maintenance are described in the ISO/IEC Directives, Part 1. In particular, the different approval criteria needed for the different types of ISO documents should be noted. This document was drafted in accordance with the editorial rules of the ISO/IEC Directives, Part 2 (see www.iso.org/directives).

Attention is drawn to the possibility that some of the elements of this document may be the subject of patent rights. ISO shall not be held responsible for identifying any or all such patent rights. Details of any patent rights identified during the development of the document will be in the Introduction and/or on the ISO list of patent declarations received (see www.iso.org/patents).

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For an explanation of the voluntary nature of standards, the meaning of ISO specific terms and expressions related to conformity assessment, as well as information about ISO's adherence to the World Trade Organization (WTO) principles in the Technical Barriers to Trade (TBT), see www.iso.org/iso/foreword.html.

This document was prepared by Technical Committee ISO/TC 229, *Nanotechnologies*, in collaboration with the European Committee for Standardization (CEN) Technical Committee CEN/TC 352, *Nanotechnologies*, in accordance with the Agreement on technical cooperation between ISO and CEN (Vienna Agreement).

This second edition cancels and replaces the first edition (ISO/TS 80004-6:2013), which has been technically revised throughout.

A list of all parts in the ISO/TS 80004 series can be found on the ISO website.

Any feedback or questions on this document should be directed to the user's national standards body. A complete listing of these bodies can be found at www.iso.org/members.html.

Introduction

Measurement and instrumentation techniques have effectively opened the door to modern nanotechnology. Characterization is key to understanding the properties and function of all nano-objects.

Nano-object characterization involves interactions between people with different backgrounds and from different fields. Those interested in nano-object characterization might, for example, be materials scientists, biologists, chemists or physicists, and might have a background that is primarily experimental or theoretical. Those making use of the data extend beyond this group to include regulators and toxicologists. To avoid any misunderstandings, and to facilitate both comparability and the reliable exchange of information, it is essential to clarify the concepts, to establish the terms for use and to establish their definitions.

The terms are classified under the following broad headings:

- [Clause 3](#): General terms;
- [Clause 4](#): Terms related to size and shape measurement;
- [Clause 5](#): Terms related to chemical analysis;
- [Clause 6](#): Terms related to measurement of other properties.

These headings are intended as a guide only, as some techniques can determine more than one property. Subclause [4.1](#) lists the overarching measurands that apply to the rest of [Clause 4](#). Other measurands are more technique-specific and are placed in the text adjacent to the technique.

It should be noted that most techniques require analysis in a non-native state and involve sample preparation, e.g. placing the nano-objects on a surface or placing them in a specific fluid or vacuum. This could change the nature of the nano-objects.

The order of the techniques in this document should not be taken to indicate a preference and the techniques listed in this document are not intended to be exhaustive. Equally, some of the techniques listed in this document are more popular than others in their usage in analysing certain properties of nano-objects. [Table 1](#) lists alphabetically the common techniques for nano-object characterization.

Subclause [4.5](#) provides definitions of microscopy methods and related terms. For these abbreviated terms, note that the final “M”, given as “microscopy”, can also mean “microscope” depending on the context. For definitions relating to the microscope, the word “method” can be replaced by the word “instrument” where that appears.

[Clause 5](#) provides definitions of terms related to chemical analysis. For these abbreviated terms, note that the final “S”, given as “spectroscopy”, can also mean “spectrometer” depending on the context. For definitions relating to the spectrometer, the word “method” can be replaced by the word “instrument” where that appears.

This document is intended to serve as a starting reference for the vocabulary that underpins measurement and characterization efforts in the field of nanotechnologies.

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Table 1 — Alphabetical list of the common techniques for nano-object characterization

Property	Common techniques
Size	analytical centrifugation atomic-force microscopy (AFM) differential mobility analysing system (DMAS) dynamic light scattering (DLS) inductively coupled plasma mass spectrometry (ICP-MS) nanoparticle tracking analysis (NTA) scanning electron microscopy (SEM) small-angle X-ray scattering (SAXS) transmission electron microscopy (TEM)
Shape	atomic-force microscopy (AFM) scanning electron microscopy (SEM) transmission electron microscopy (TEM)
Surface area	Brunauer–Emmett–Teller (BET) method
“Surface” chemistry	Raman spectroscopy secondary-ion mass spectrometry (SIMS) X-ray photoelectron spectroscopy (XPS)
Chemistry of the “bulk” sample	energy-dispersive X-ray spectroscopy (EDX) inductively coupled plasma mass spectrometry (ICP-MS) nuclear magnetic resonance (NMR) spectroscopy
Crystallinity	selected area electron diffraction (SAED) X-ray diffraction (XRD)
Electrokinetic potential in suspensions	electrophoretic mobility

Nanotechnologies — Vocabulary —

Part 6: Nano-object characterization

1 Scope

This document defines terms related to the characterization of nano-objects in the field of nanotechnologies. It is intended to facilitate communication between organizations and individuals in research, industry and other interested parties and those who interact with them.

2 Normative references

There are no normative references in this document.

3 Terms and definitions

ISO and IEC maintain terminological databases for use in standardization at the following addresses:

- ISO Online browsing platform: available at <https://www.iso.org/obp>
- IEC Electropedia: available at <http://www.electropedia.org/>

3.1

nanoscale

length range approximately from 1 nm to 100 nm

Note 1 to entry: Properties that are not extrapolations from a larger size are predominantly exhibited in this length range.

[SOURCE: ISO/TS 80004-1:2015, 2.1]

3.2

nano-object

discrete piece of material with one, two or three external dimensions in the *nanoscale* (3.1)

Note 1 to entry: The second and third external dimensions are orthogonal to the first dimension and to each other.

[SOURCE: ISO/TS 80004-1:2015, 2.5]

3.3

nanoparticle

nano-object (3.2) with all external dimensions in the *nanoscale* (3.1) where the lengths of the longest and the shortest axes of the nano-object do not differ significantly

Note 1 to entry: If the dimensions differ significantly (typically by more than three times), terms such as *nanofibre* (3.6) or *nanoplate* (3.4) may be preferred to the term “nanoparticle”.

[SOURCE: ISO/TS 80004-2:2015, 4.4]

ISO/TS 80004-6:2020(E)**3.4****nanoplate**

nano-object (3.2) with one external dimension in the *nanoscale* (3.1) and the other two external dimensions significantly larger

Note 1 to entry: The larger external dimensions are not necessarily in the nanoscale.

Note 2 to entry: See 3.3, Note 1 to entry.

[SOURCE: ISO/TS 80004-2:2015, 4.6]

3.5**nanorod**

solid *nanofibre* (3.6)

[SOURCE: ISO/TS 80004-2:2015, 4.7]

3.6**nanofibre**

nano-object (3.2) with two external dimensions in the *nanoscale* (3.1) and the third dimension significantly larger

Note 1 to entry: The largest external dimension is not necessarily in the nanoscale.

Note 2 to entry: The terms “nanofibril” and “nanofilament” can also be used.

Note 3 to entry: See 3.3, Note 1 to entry.

[SOURCE: ISO/TS 80004-2:2015, 4.5]

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3.7**nanotube**

hollow *nanofibre* (3.6)

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[SOURCE: ISO/TS 80004-2:2015, 4.8]

3.8**quantum dot**

nanoparticle (3.3) or region which exhibits quantum confinement in all three spatial directions

[SOURCE: ISO/TS 80004-12:2016, 4.1, modified — Note 1 to entry has been deleted.]

3.9**particle**

minute piece of matter with defined physical boundaries

Note 1 to entry: A physical boundary can also be described as an interface.

Note 2 to entry: A particle can move as a unit.

Note 3 to entry: This general particle definition applies to *nano-objects* (3.2).

[SOURCE: ISO/TS 80004-2:2015, 3.1]

3.10**agglomerate**

collection of weakly or medium strongly bound *particles* (3.9) where the resulting external surface area is similar to the sum of the surface areas of the individual components

Note 1 to entry: The forces holding an agglomerate together are weak forces, for example van der Waals forces or simple physical entanglement.

Note 2 to entry: Agglomerates are also termed “secondary particles” and the original source particles are termed “primary particles”.

[SOURCE: ISO/TS 80004-2:2015, 3.4]

3.11

aggregate

particle (3.9) comprising strongly bonded or fused particles where the resulting external surface area is significantly smaller than the sum of surface areas of the individual components

Note 1 to entry: The forces holding an aggregate together are strong forces, for example covalent or ionic bonds, or those resulting from sintering or complex physical entanglement, or otherwise combined former primary particles.

Note 2 to entry: Aggregates are also termed “secondary particles” and the original source particles are termed “primary particles”.

[SOURCE: ISO/TS 80004-2:2015, 3.5]

3.12

aerosol

system of solid or liquid *particles* (3.9) suspended in gas

[SOURCE: ISO 15900:2009, 2.1]

3.13

suspension

heterogeneous mixture of materials comprising a liquid and a finely dispersed solid material

[SOURCE: ISO 4618:2014, 2.246]

3.14

dispersion

multi-phase system in which discontinuities of any state (solid, liquid or gas: discontinuous phase) are distributed in a continuous phase of a different composition or state

Note 1 to entry: This term also refers to the act or process of producing a dispersion; in this context the term “dispersion process” should be used.

Note 2 to entry: If solid *particles* (3.9) are distributed in a liquid, the dispersion is referred to as a *suspension* (3.13). If the dispersion consists of two or more immiscible liquid phases, it is termed an “emulsion”. A suspoemulsion consists of both solid and liquid phases distributed in a continuous liquid phase.

[SOURCE: ISO/TR 13097:2013, 2.5, modified — In the definition, “in general, microscopic” has been deleted and “distributed” has replaced “dispersed”. Notes 1 and 2 to entry have replaced the original Note 1 to entry.]

4 Terms related to size and shape measurement

4.1 Terms related to measurands for size and shape

4.1.1

particle size

linear dimension of a *particle* (3.9) determined by a specified measurement method and under specified measurement conditions

Note 1 to entry: Different methods of analysis are based on the measurement of different physical properties. Independent of the particle property actually measured, the particle size can be reported as a linear dimension, e.g. as the equivalent spherical diameter.

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4.1.2

particle size distribution

distribution of the quantity of *particles* (3.9) as a function of *particle size* (4.1.1)

Note 1 to entry: Particle size distribution may be expressed as cumulative distribution or a distribution density (distribution of the fraction of material in a size class, divided by the width of that class).

Note 2 to entry: The quantity can be, for example, number, mass or volume based.

4.1.3

particle shape

external geometric form of a *particle* (3.9)

[SOURCE: ISO 3252:2019, 3.1.59, modified — “powder” has been deleted before “particle”.]

4.1.4

aspect ratio

ratio of length of a *particle* (3.9) to its width

[SOURCE: ISO 14966:2019, 3.7]

4.1.5

equivalent diameter

diameter of a sphere that produces a response by a given particle-size measurement method that is equivalent to the response produced by the *particle* (3.9) being measured

Note 1 to entry: Physical properties are, for example, the same settling velocity or electrolyte solution displacing volume or projection area under a microscope. The physical property to which the equivalent diameter refers should be indicated using a suitable subscript (see ISO 9276-1:1998), e.g. subscript “V” for equivalent volume diameter and subscript “S” for equivalent surface area diameter.

Note 2 to entry: For discrete-particle-counting, light-scattering instruments, an equivalent optical diameter is used.

Note 3 to entry: Other parameters, e.g. the effective density of the particle in a fluid, are used for the calculation of the equivalent diameter such as Stokes diameter or sedimentation equivalent diameter. The parameters used for the calculation should be reported additionally.

Note 4 to entry: For inertial instruments, the aerodynamic diameter is used. Aerodynamic diameter is the diameter of a sphere of density 1 000 kg m⁻³ that has the same settling velocity as the particle in question.

4.2 Terms related to scattering techniques

4.2.1

radius of gyration

measure of the distribution of mass about a chosen axis, given as the square root of the moment of inertia about that axis divided by the mass

Note 1 to entry: For *nano-object* (3.2) characterization, physical methods that measure radius of gyration to determine *particle size* (4.1.1) include static *light scattering* (4.2.5), *small-angle neutron scattering* (4.2.2) and *small-angle X-ray scattering* (4.2.4).

[SOURCE: ISO 14695:2003, 3.4, modified — Note 1 to entry has been added.]

4.2.2

small-angle neutron scattering

SANS

method in which a beam of neutrons is scattered from a sample and the scattered neutron intensity is measured for small angle deflection

Note 1 to entry: The scattering angle is usually between 0,5° and 10° in order to study the structure of a material on the length scale of approximately 1 nm to 200 nm. The method provides information on the sizes of the *particles* (3.9) and, to a limited extent, the shapes of the particles dispersed in a homogeneous medium.